

<b>Notice of References Cited</b>	Application/Control No. 10/627,629	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Vijay B. Chawan	Art Unit 2626	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,996,522	02-2006	Chen, Fang-Chu	704/219
*	B	US-7,024,355	04-2006	Nomura, Toshiyuki	704/221
*	C	US-7,117,146	10-2006	Gao, Yang	704/200.1
*	D	US-6,108,626	08-2000	Cellario et al.	704/230
*	E	US-6,263,307	07-2001	Arslan et al.	704/226
*	F	US-5,495,555	02-1996	Swaminathan, Kumar	704/207
*	G	US-6,182,030	01-2001	Hagen et al.	704/201
*	H	US-5,966,689	10-1999	McCree, Alan V.	704/226
*	I	US-6,055,496	04-2000	Heidari et al.	704/222
*	J	US-6,148,288	11-2000	Park, Sung-hee	704/500
*	K	US-6,687,666	02-2004	Ehara et al.	704/207
*	L	US-6,732,070	05-2004	Rotola-Pukkila et al.	704/219
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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